

Notice of References Cited	Application/Control No. 10/015,414	Applicant(s)/Patent Under Reexamination FAN ET AL.	
	Examiner Ly D Pham	Art Unit 2818	Page 1 of 1

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*	B	US-2003/0067807 A1	04-2003	Lin et al.	365/185.28
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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